Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
09/943,347	TAKEO, HIDEYA
Examiner	Art Unit
Christopher L. Lavin	2621

	SEVD	CHED	-		
	SEARCHED				
Class	Subclass	Date	Examiner		
382	128,159, 130-132, 160, 170	6/22/2005	CLL		
382	190, 199	6/22/2005	CLL		
382	203	6/22/2005	CLL		
382	256-265	6/22/2005	CLL		
128	920	6/22/2005	CLL		
128	922-925	6/22/2005	CLL		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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